Application No.	Applicant(s)
10/003.831	NAKANO ET AL.
Examiner	Art Unit
Aaron W. Carter	2625
and MPEP 1308.	plication. If not included
<u>st 29, 2005</u> .	
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3.	
6. Interview Summary Paper No./Mail Da 08), 7. Examiner's Amendo	te
	Examiner  Aaron W. Carter  Pars on the cover sheet with the co (OR REMAINS) CLOSED in this application is subject to and MPEP 1308.  St 29, 2005.  Ander 35 U.S.C. § 119(a)-(d) or (f).  Be been received.  Be been received in Application No cuments have been received in this  of this communication to file a reply MENT of this application.  Ander 35 U.S.C. § 119(a)-(d) or (f).  Be been received in Application No cuments have been received in this  of this communication to file a reply MENT of this application.  Ander 35 U.S.C. § 119(a)-(d) or (f).  Be been received.  Be been received.  Be been received in Application No cuments have been received in this  of this communication to file a reply MENT of this application.  Ander 35 U.S.C. § 119(a)-(d) or (f).  Be been received.  Be been received.  Be been received in Application No cuments have been received in this  of this communication to file a reply MENT of this application.  Ander 35 U.S.C. § 119(a)-(d) or (f).  Be been received.  Be been r

Application/Control Number: 10/003,831 Page 2

Art Unit: 2625

## **DETAILED ACTION**

1. This action is responsive to papers filed on August 29, 2005.

## Response to Amendment

2. In response to applicant's amendment received on August 29, 2005, all requested changes to the specification and claims have been entered. Claims 13-16 have been added. Claims 1-12 have been cancelled.

## Allowable Subject Matter

- 3. Claims 13-16 are allowed.
- 4. The following is an examiner's statement of reasons for allowance, these reasons are the same reasons as indicated in the previous office action mailed on May 3, 2005:

As to claims 13, 14 and 16, none of the prior art teach or fairly suggests a bad mark indicating a defective individual substrate, a individual substrate mark for recognizing a position and inclination of at least one individual substrate, wherein said bad mark is indicated on said individual substrate mark. USPN 6,079,098 to Soellner et al. discloses a bad mark for indicating a defective individual substrate along with an individual substrate mark for indicating position and inclination of an individual substrate, he does not teach or fairly suggest that the bad mark is indicated on the individual substrate mark.

Art Unit: 2625

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## Conclusion

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Aaron W. Carter whose telephone number is (571) 272-7445. The examiner can normally be reached on 8am - 4:30 am (Mon. - Fri.).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Bhavesh Mehta can be reached on (571) 272-7453. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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